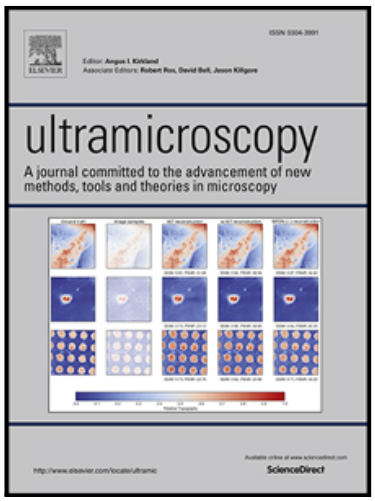

Quasi-parallel precession diffraction: Alignment method for scanning transmission electron microscopes

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Highlights

- A general method to align a quasi-parallel beam on a scanning transmission electron microscope (STEM) is proposed.
- 6-coils and 8-coils precession electron diffraction (PED) alignment is presented for the STEM mode.
- Quasi-parallel PED-STEM is achieved on a JEOL 2100 LaB_6 with 12 nm of beam diameter, 0.5 mrad of convergence angle and 1.0 degree of beam precession.